

CsPbBr₃-DMSO merged perovskite micro-bricks for efficient X-ray detection

Tongyu Shi^{1,2,§}, Wenjun Liu^{1,3,§}, Jiongtao Zhu¹, Xiongsheng Fan¹, Zhengyu Zhang¹, Xingchen He¹, Rui He¹, Jiahong Wang^{1,2}, Kezhen Chen^{1,2}, Yongshuai Ge^{1,2}, Xiangming Sun⁴, Yanliang Liu^{1,2} (✉), Paul K. Chu⁵, and Xue-Feng Yu^{1,2} (✉)

¹ Shenzhen Institute of Advanced Technology, Chinese Academy of Sciences, Shenzhen 518055, China

² University of Chinese Academy of Sciences, Beijing 100049, China

³ Nano Science and Technology Institute, University of Science and Technology of China, Suzhou 215123, China

⁴ Key Laboratory of Quark and Lepton Physics (MOE), Central China Normal University, Wuhan 430079, China

⁵ Department of Physics, Department of Materials Science and Engineering, and Department of Biomedical Engineering, City University of Hong Kong, Hong Kong 999077, China

[§] Tongyu Shi and Wenjun Liu contributed equally to this work.

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ABSTRACT

Inorganic perovskite wafers with good stability and adjustable sizes are promising in X-ray detection but the high synthetic temperature is a hindrance. Herein, dimethyl sulfoxide (DMSO) is used to prepare the CsPbBr₃ micro-bricks powder at room temperature. The CsPbBr₃ powder has a cubic shape with few crystal defects, small charge trap density, and high crystallinity. A trace amount of DMSO attaches to the surface of the CsPbBr₃ micro-bricks via Pb–O bonding, forming the CsPbBr₃-DMSO adduct. During hot isostatic processing, the released DMSO vapor merges the CsPbBr₃ micro-bricks, producing a compact and dense CsPbBr₃ wafer with minimized grain boundaries and excellent charge transport properties. The CsPbBr₃ wafer shows a large mobility-lifetime ($\mu\tau$) product of $5.16 \times 10^{-4} \text{ cm}^2 \cdot \text{V}^{-1}$, high sensitivity of $14,430 \mu\text{C} \cdot \text{Gy}_{\text{air}}^{-1} \cdot \text{cm}^{-2}$, low detection limit of $564 \text{ nGy}_{\text{air}} \cdot \text{s}^{-1}$, as well as robust stability in X-ray detection. The results reveal a novel strategy with immense practical potential pertaining to high-contrast X-ray detection.

KEYWORDS

CsPbBr₃-DMSO, inorganic perovskites wafer, grain growth, crystal defect, X-ray detector

1 Introduction

X-ray detection is required by medical diagnosis, industrial non-destructive inspection, nuclear reaction monitoring, and other fields [1–3]. There are indirect and direct techniques to detect X-ray. In the indirect mode, X-ray photons are converted to visible light by scintillators and the light is detected by a photodetector. Unfortunately, indirect X-ray imaging suffers from the low spatial resolution and quantum efficiency due to inevitable visible light scattering [4]. In contrast, direct X-ray detectors made of semiconductors absorb X-ray absorption directly and convert X-ray into electrical signals, thus boasting higher sensitivity and spatial imaging resolution [5]. The common direct X-ray conversion semiconductors are silicon (Si), amorphous selenium (a-Se), and Cd(Zn)Te. Nevertheless, Si and a-Se suffer from insufficient X-ray absorption due to the small atomic number and a-Se has lower mobility-lifetime ($\mu\tau$) products ($\mu\tau$ of $10^{-7} \text{ cm}^2 \cdot \text{V}^{-1}$) [6]. Cd(Zn)Te is a standard material for hard X-ray detectors but the disadvantages are the high cost and small crystal size [7]. Therefore, it is important to identify semiconducting materials for more efficient direct X-ray detection.

Inorganic metal halide perovskites have emerged to be viable

materials for high-contrast X-ray detection due to the large X-ray attenuation coefficient, high carrier mobility, long carrier lifetime, low trap density, and excellent material stability [8–13]. Perovskite single crystals can be prepared in solutions with sufficient thickness and high carrier mobility-lifetime [14, 15]. CsPbBr₃ single crystals were first used in X-ray detection in 2013 [16]. Lin et al. have demonstrated the potential of solution-grown CsPbBr₃ single crystals for X-ray imaging [17]. After that, Hao and co-workers have reported CsPbBr₃ X-ray detectors with a sensitivity of $6021.99 \mu\text{C} \cdot \text{Gy}_{\text{air}}^{-1} \cdot \text{cm}^{-2}$ and detection limit of $1.89 \mu\text{Gy}_{\text{air}} \cdot \text{s}^{-1}$ [18]. In X-ray imaging, a detector with comparable size to the object being analyzed is necessary because the X-ray refractive index is about 1.0. However, preparation of perovskite single crystals with a large size is challenging and time consuming [19]. In order to absorb high-power X-ray, the thickness of the perovskite film should be hundreds of micrometers, but common solution-based methods such as spin coating and blade coating are commonly employed to produce perovskite films with nanometer-scale thickness designed for solar cells and light-emitting devices [20, 21]. In fact, it is difficult to prepare thick perovskite films due to the low concentration of inorganic perovskite precursors in solutions besides low materials utilization.

In order to construct a perovskite X-ray converter with a scalable size and the required thickness, an isostatic process has been proposed to compact the perovskite powder to form a polycrystalline perovskite wafer instead of single crystal for X-ray detection and imaging [22]. Tang et al. have developed X-ray detectors consisting of the $\text{Cs}_2\text{AgBiBr}_6$ wafer with a high sensitivity of $250 \mu\text{C}\cdot\text{Gy}_{\text{air}}^{-1}\cdot\text{cm}^{-2}$ and low signal drifts [23]. Heiss et al. have used $\text{Cs}_3\text{Bi}_2\text{Br}_3\text{I}_6$ to fabricate self-healing X-ray detectors with good sustainability and low detection limit [24]. However, the perovskite powder prepared by conventional dry mechanical grinding usually has poor surface morphology and high defect density [25, 26]. Furthermore, solvent-based synthesis of perovskite powders is difficult on a large scale due to the low solubility of the perovskite precursors [27]. Polycrystalline inorganic perovskite wafers normally contain voids and grain boundaries, which decrease the X-ray absorption efficiency and hinder charge transport and collection [23]. In this respect, a high temperature is usually employed to enhance the crystallinity of inorganic perovskite wafers. However, the high temperature inevitably introduces crystal defects, which also renders the integration of perovskite wafers into X-ray imaging flat panels difficult [28, 29].

Herein, a solvent-based approach is designed and demonstrated to produce CsPbBr_3 micro-bricks for compact microcrystalline perovskite wafers for X-ray detectors. The CsPbBr_3 powder is prepared by mechanical grinding and then cultivated in dimethyl sulfoxide (DMSO) to produce CsPbBr_3 micro-bricks with a cubic shape, high crystallinity, and excellent optoelectronic properties. A trace amount of DMSO attaches to the surface of CsPbBr_3 micro-bricks via Pb–O bonding, forming the CsPbBr_3 -DMSO adduct. During hot isostatic processing, the DMSO vapor released from the adduct further promotes CsPbBr_3 grain growth, which subsequently merges CsPbBr_3 micro-bricks at a low temperature of 100°C to obtain compact and dense CsPbBr_3 wafer with minimized grain boundaries. The wafer exhibits excellent electrical properties such as reduced resistance of $3.16 \times 10^8 \Omega\cdot\text{cm}$ and high mobility-lifetime product of $5.16 \times 10^{-4} \text{cm}^2\cdot\text{V}^{-1}$, which are comparable to those of the CsPbBr_3 single crystal. The direct X-ray detector with the structure of Au/perovskite/[6,6]-phenyl C61 butyric acid methyl (PCBM)/Au shows a high sensitivity of $14,430 \mu\text{C}\cdot\text{Gy}_{\text{air}}^{-1}\cdot\text{cm}^{-2}$ and low detection limit of $564 \text{nGy}_{\text{air}}\cdot\text{s}^{-1}$. The detector also has excellent stability at an electric field of $40 \text{V}\cdot\text{mm}^{-1}$ and dose rate of $1620 \mu\text{Gy}_{\text{air}}\cdot\text{s}^{-1}$.

2 Materials and methods

2.1 Chemicals

PbBr_2 (lead bromide, 99%, Aladdin), CsBr (cesium bromide, 99.5%, Aladdin), and organic solvents such as dimethyl sulfoxide (DMSO, AR, 99%), acetone (AR, 99%), and isopropyl (AR, 99%) were supplied from Sigma-Aldrich. PCBM (AR, 99%) was provided by Xi'an Polymer Light Corp. The gold particles (product No. Au11474 $3 \times 3 \text{mm}$) used to prepare the gold electrode were purchased from Zhong Nuo New Materials Co., Ltd. (Beijing, China). All the chemicals were used as received without further purification.

2.2 Synthesis of CsPbBr_3 micro-bricks

The pristine CsPbBr_3 powder was synthesized by mechanical milling. The reactants (17.36 g, $\text{CsBr}/\text{PbBr}_2 = 1/1$) were milled with 40 g agate balls for 2 h at 400 rpm in a planetary ball mill machine. In the following, the pristine CsPbBr_3 powder was cultivated in DMSO (1 mL per 1 g of powder) under stirring at room temperature, and then extracted from isopropanol. After

drying at 40°C for overnight, CsPbBr_3 micro-bricks were obtained.

2.3 Preparation of CsPbBr_3 wafer

The pristine CsPbBr_3 and CsPbBr_3 micro-bricks powders were squashed onto the perovskite wafer with mirror-like surface, respectively. Subsequently, the perovskite wafers were further heated at 150°C for 2 h to evaporate the residual DMSO, obtaining complete CsPbBr_3 wafers.

2.4 Device fabrication

The X-ray detector has device configuration of Au (80 nm)/PCBM/ CsPbBr_3 wafer/Au (80 nm). The PCBM solution ($20 \text{mg}\cdot\text{mL}^{-1}$) layer was spin-coated on the free-standing perovskite wafer at 1500 rpm for 30 s. The Au film was deposited onto both sides of the CsPbBr_3 /PCBM wafer by thermal evaporation. The X-ray detector has an effective device area of 0.01cm^2 ($1 \text{mm} \times 1 \text{mm}$), defined by the overlapping area of the top and bottom Au electrodes.

3 Results and discussion

In X-ray detectors, a thick perovskite film is required to absorb high energy X-ray. Herein, preparation of the high-quality raw CsPbBr_3 powder is illustrated in Fig. 1(a). A large amount of CsPbBr_3 powder is first synthesized by simple mechanical grinding (Fig. S1 in the Electronic Supplementary Material (ESM)). However, the as-prepared CsPbBr_3 powder has an irregular morphology with a wide grain size distribution ranging from several nanometers to micrometers (Fig. S2 in the ESM), and so DMSO is introduced to modify the CsPbBr_3 powder. As shown in Fig. S3 in the ESM, the CsPbBr_3 powder is immersed in DMSO and stirred to mix completely. After aging for 2 h, the yellow CsPbBr_3 mixture converts to yellowish green and isopropanol is added as an anti-solvent to precipitate CsPbBr_3 . In the synthesis, the CsPbBr_3 powder dissolves and regrows to form cubic CsPbBr_3 micro-bricks with a large size of several micrometers, as shown in Fig. 1(b) and Fig. S4 in the ESM.

To monitor the structural changes, X-ray diffraction (XRD) is conducted as shown in Fig. 1(c). The diffraction patterns of the pristine CsPbBr_3 powder and CsPbBr_3 micro-bricks can be well indexed to the standard monoclinic perovskite phase of CsPbBr_3 (PDF#18-0364). In particular, the stronger XRD peaks of CsPbBr_3 micro-bricks indicate the improved crystallinity compared with the pristine CsPbBr_3 . Besides, the pristine CsPbBr_3 powder shows the strongest diffraction peak at $2\theta = 21.50^\circ$, which is corresponding to the (110) facet of the monoclinic CsPbBr_3 phase. In contrast, the CsPbBr_3 micro-bricks exhibit two impressive diffraction peaks at $2\theta = 15.21^\circ$ and 30.70° assigned to the (100) and (200) facets of the monoclinic CsPbBr_3 phase, respectively, which demonstrates the $\langle 100 \rangle$ preferred orientation selectively [30–31]. The pattern of the yellowish green precipitate can be indexed to Cs_4PbBr_6 (PDF#54-0750) with the prominent peaks of (024). The formation of intermediate Cs_4PbBr_6 can be explained by the solubility difference between PbBr_2 and CsBr . Based on the above observations, it is assumed that the synthesis of CsPbBr_3 micro-bricks can be divided into three stages: dissolution, recrystallization, and precipitation. As illustrated in Fig. S5 in the ESM, in the first stage, the pristine perovskite powder dissolves partially in DMSO. Since Pb^{2+} is more soluble in this condition than Cs^+ , Cs_4PbBr_6 is formed with Cs-rich $\langle 012 \rangle$ preferred orientation [32]. After aging for a while, dynamic equilibrium in the DMSO solution is achieved, and Cs_4PbBr_6 recrystallizes to the appearance of micrometer-scale flakes gradually, as shown in Fig. S6 in the ESM [32, 33]. With the addition of anti-solvent, the

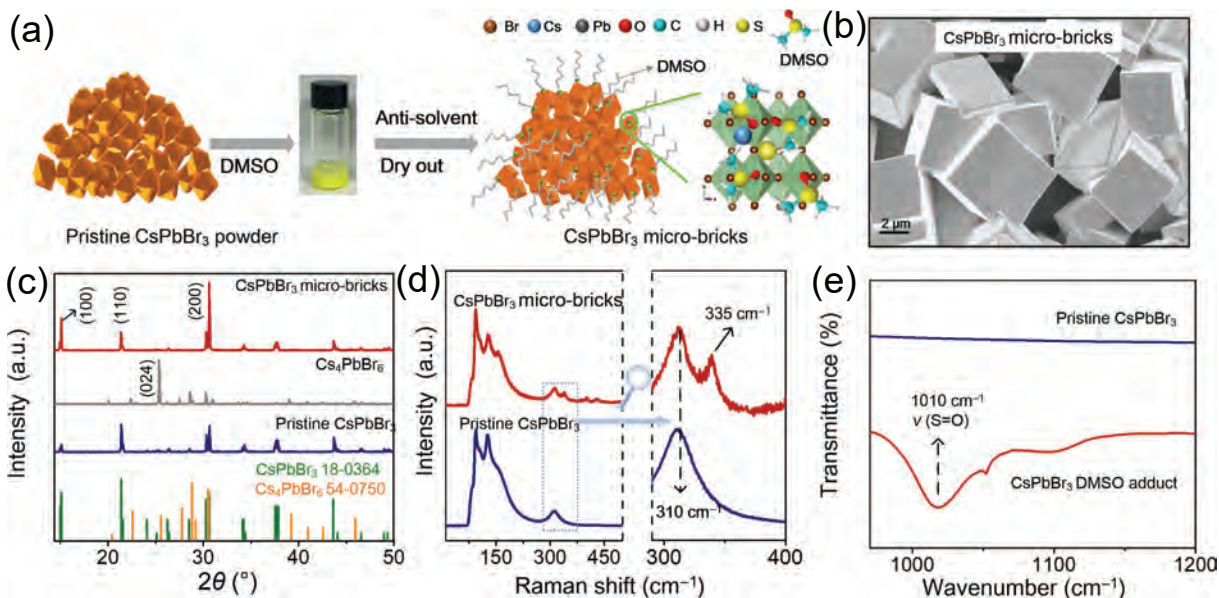


Figure 1 Synthesis and characterization of CsPbBr₃ micro-bricks and CsPbBr₃ DMSO adduct. (a) Schematic illustration of the preparation of the CsPbBr₃ micro-bricks powder. (b) SEM image of the CsPbBr₃ micro-bricks. (c) XRD patterns of the pristine CsPbBr₃, Cs₄PbBr₆, and CsPbBr₃ micro-bricks. (d) Raman scattering spectra and (e) FTIR spectra of the pristine CsPbBr₃ and CsPbBr₃ DMSO adduct (inset showing the Tauc plot).

dissolved PbBr₂ and CsBr undergo rapid crystallization and precipitate from the solution. Owing to the lower atom density and energy, CsPbBr₃ grows along the <100> orientation and finally the micro-bricks are obtained [30]. It is worth noting that, the aging time and the type of the anti-solvents play an important role in determining the formation of the CsPbBr₃ micro-bricks (Figs. S7 and S8 in the ESM). Moreover, the CsPbBr₃ powder is exposed to 85 °C and 85% relative humidity condition to evaluate the stability. After 21 days of aging under high temperature and humidity, compared with the pristine CsPbBr₃ transformed to CsPb₂Br₅ phase (PDF#25-0211), the CsPbBr₃ micro-bricks exhibit significantly improved tolerance to moisture and temperature with stable CsPbBr₃ cubic perovskite phase (Fig. S9 in the ESM).

The Raman scattering spectra are presented in Fig. 1(d). According to previous reports, the second order Raman band at 310 cm⁻¹ observed from all the samples indicates the presence of CsPbBr₃ [34] and the Raman peaks below 200 cm⁻¹ are similar. The peak at 335 cm⁻¹ reveals that a small amount of DMSO remains in CsPbBr₃ micro-bricks [35]. To further investigate the structure, the Fourier-transform infrared (FTIR) results are displayed in Fig. 1(e). In contrast to the pristine CsPbBr₃, the CsPbBr₃ micro-bricks exhibits an additional peak at 1011 cm⁻¹ ascribed to stretching of S=O in DMSO. Generally, the FTIR peak of S=O of DMSO is at 1048 cm⁻¹ and the decrease in the vibration frequencies from 1048 to 1011 cm⁻¹ is related to weaker bonding strength of S=O, indicating coordination between CsPbBr₃ and DMSO [36, 37]. The X-ray photoelectron spectroscopy (XPS) is further conducted to investigate the formation mechanism of CsPbBr₃-DMSO adducts. As shown in Fig. S10 in the ESM, the peaks at 137.9 and 142.8 eV are attributed to Pb 4f_{7/2} and 4f_{5/2}, respectively (Fig. 1(c)). Compared with the pristine CsPbBr₃, the Pb 4f of adduct presents an obvious shift to higher binding energy and two shoulders (~ 139.5 and ~ 144.2 eV), suggesting the existence of Pb–O coordination [38, 39]. It has been shown that formation of intermediate adducts between the lead halide perovskite and DMSO proceeds via the Pb–O bridge [40, 41]. Hence, it can be postulated that the CsPbBr₃ micro-bricks powder contains some CsPbBr₃-DMSO adducts. Moreover, as shown in Fig. S11 in the ESM, the disappearance of the S=O peaks after 100 °C heating indicates that CsPbBr₃-DMSO complex can be easily broken down to CsPbBr₃ and DMSO vapor. The released DMSO vapor is expected to enhance the growth of the CsPbBr₃ crystal.}

As shown in Fig. 2, the pristine CsPbBr₃ and CsPbBr₃ micro-bricks are squashed into perovskite wafers by hot isostatic pressing at 100 °C and 10 MPa for 1 h. The samples were further heated at 150 °C for 2 h on a hot plate to form the CsPbBr₃ wafers. The thickness of perovskite wafer varies with the amount of powder added, ranging from 300 to 600 μm (Fig. S12 in the ESM). Scanning electron microscopy (SEM) and atom force microscopy (AFM) are conducted to examine the morphology of the two samples. The CsPbBr₃ wafer exhibits an incomplete and non-uniform surface morphology with a small grain size and lots of pinholes as shown in Fig. 2(b), and the interior shows many voids and grain boundaries as shown in Fig. 2(c), which are detrimental to X-ray absorption as well as charge transport and collection. The same surface morphology can be observed by AFM image as shown in Fig. 2(d). In contrast, the wafer made of CsPbBr₃ micro-bricks exhibits compact surface with a large grain size and full coverage, as well dense interior with little voids and merged grain boundaries as shown in Figs. 2(e) and 2(f). The improved morphology can be attributed to the *in situ* growth of CsPbBr₃ induced by DMSO vapor during hot isostatic processing. The AFM image in Fig. 2(g) corroborates grain growth and merged grain boundaries, and the pristine and CsPbBr₃ micro-bricks wafers exhibit comparable surface roughness of 46.1 and 28.5 nm in Fig. S13 in the ESM, respectively. Therefore, it is reasonable to speculate that DMSO plays a vital role in the growth of the CsPbBr₃ micro-bricks. The influence of humidity on the wafer is also investigated. After 14 days in air (25 °C and 60% relative humidity), the CsPbBr₃ micro-bricks wafer still maintains good morphology, while the pristine CsPbBr₃ wafer exhibits obvious decomposition along grain boundaries (Fig. S14 in the ESM).

The steady-state photoluminescence (PL) and time-resolved photoluminescence (TRPL) characteristics are analyzed to determine the optical properties, as shown in Figs. 3(a) and 3(b). The wafer made of CsPbBr₃ micro-bricks exhibits significantly higher PL intensity than the CsPbBr₃ wafer and the PL peak red-shifts from 515 to 518 nm indicative of a larger grain size and enhanced crystallinity. The diffuse reflectance data are presented in Fig. S15 in the ESM and the optical absorption is analyzed by Kubelka–Munk equation. In the wavelength range of 500–550 nm, the reflectance of the pristine CsPbBr₃ is slightly higher than that of the CsPbBr₃ micro-bricks powder caused by light scattering

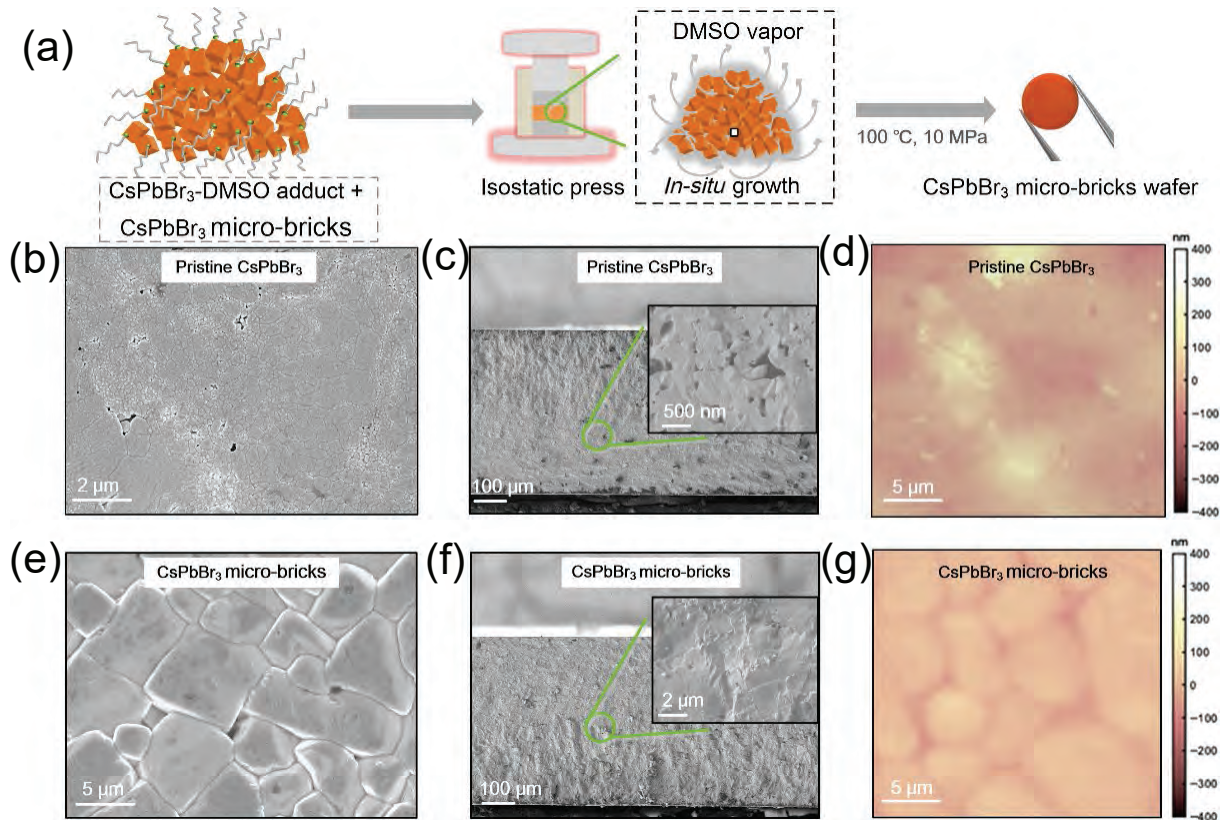


Figure 2 Fabrication and morphologies of CsPbBr₃ wafers. (a) Schematic illustration of CsPbBr₃ micro-bricks isostatic pressing of the perovskite wafer. SEM and AFM images of (b), (c), and (d) pristine CsPbBr₃ and (e), (f), and (g) CsPbBr₃ micro-bricks perovskite wafer.

at grain boundaries. By fitting the spectra with the Tauc relationship, the bandgap E_g values of the pristine CsPbBr₃ and CsPbBr₃ micro-bricks are calculated to be 2.27 and 2.25 eV, respectively. The narrower bandgap can be attributed to the larger grain size [42]. The TRPL of the untreated CsPbBr₃ and CsPbBr₃ micro-bricks wafers can be fitted by exponential functions, where A_1 and A_2 are the fractional contributions of the PL decay lifetime. A short lifetime (τ_1) corresponds to fast decay related to quenching (including charge transfer) and defects, whereas a long lifetime (τ_2) corresponds to slow decay due to recombination. The pristine CsPbBr₃ wafer shows a short lifetime τ_1 of 2.29 ns and long lifetime τ_2 of 11.74 ns. In comparison, the CsPbBr₃ micro-bricks wafer exhibits an obviously longer short lifetime τ_1 of 5.70 ns and long lifetime τ_2 of 33.07 ns. τ_{ave} improves from 6.80 to 25.92 ns, suggesting a smaller defect density and enhanced carrier transport in the CsPbBr₃ micro-bricks wafer. The TRPL parameters are listed in Table S1 in the ESM. The CsPbBr₃ micro-bricks wafer also has higher crystallinity than the pristine CsPbBr₃ wafer as shown in Fig. 3(c) [43], which is consistent with Fig. 1(d). All in all, the CsPbBr₃ micro-bricks wafer has better crystallinity and lower defect density boding well for charge transport and collection.

To determine the optoelectronic properties, photoconductivity measurements are carried out as shown in Fig. 3(g). The photocurrent response is monitored by applying voltages from 0 to 50 V as shown in Fig. 3(g). The Hecht formula is employed to fit the photocurrent–voltage curve (Eq. (1))

$$I = I_0 \mu \tau V / L^2 (1 - \exp(-L^2 / \mu \tau V)) \quad (1)$$

where I_0 is the saturated current, L is the CsPbBr₃ wafer thickness, and V is the applied voltage. The $\mu \tau$ products of the pristine CsPbBr₃ and CsPbBr₃ micro-bricks wafers are determined to be 1.66×10^{-5} and 5.16×10^{-4} cm²·V⁻¹, respectively, and a bigger $\mu \tau$ product normally indicates higher crystallinity and lower defect

density. The ion migration of perovskite wafer was further investigated through Kelvin probe force microscopy (KPFM) measurement (Fig. S16 in the ESM), and the CsPbBr₃ micro-bricks wafer exhibits significantly lower electric potential than the pristine CsPbBr₃ wafer. The ions have lower formation energy and diffusion barriers compared to other mobile species in CsPbBr₃ wafer, which easily migrates under an applied electric field, leading to high electric potential. Therefore, the lower electric potential indicates reduced suppressed ion migration in the CsPbBr₃ micro-bricks wafer. As shown in Fig. 3(e), the pristine CsPbBr₃ wafer has a higher resistivity of 2.2×10^9 Ω·cm than that of CsPbBr₃ micro-bricks wafer, on account of the interior voids and holes decrease electrical conductivity, which is consistent with the SEM results.

Based on ultraviolet photoelectron spectra (UPS) results, the work function (WF) and valence band maximum (VBM) of CsPbBr₃ are calculated to be -4.51 and -5.80 eV, respectively. Combined with ultraviolet–visible (UV–Vis) spectroscopy, energy level alignment of the X-ray detector (Au/CsPbBr₃/PCBM/Au) is illustrated in Fig. S17 in the ESM. Figure 3(f) shows the current density–voltage (J – V) characteristics of the X-ray detectors constructed with the pristine CsPbBr₃ and CsPbBr₃ micro-bricks wafers. The CsPbBr₃ micro-bricks detector shows obviously higher light currents and response, confirming better X-ray detection. The dark current density of the CsPbBr₃ micro-brick detector ($3.04 \mu\text{A}\cdot\text{cm}^{-2}$) is a little higher than that of $0.896 \mu\text{A}\cdot\text{cm}^{-2}$ observed from the other detector at an electric field of $100 \text{ V}\cdot\text{mm}^{-1}$, which is consistent of the resistivity. However, the light current of the CsPbBr₃ micro-bricks detector ($21.8 \mu\text{A}\cdot\text{cm}^{-2}$) is ten times higher than that of the detector constructed with the pristine materials ($2.4 \mu\text{A}\cdot\text{cm}^{-2}$), thus facilitating low-dose and high-sensitivity X-ray detection.

To obtain more dynamic information, the time-resolved current densities of the pristine CsPbBr₃ and CsPbBr₃ micro-bricks detectors for X-ray dose rates from 1620 to $160 \mu\text{Gy}_{air}\cdot\text{s}^{-1}$ are presented in Fig. 4(a). Both detectors show decent response signals

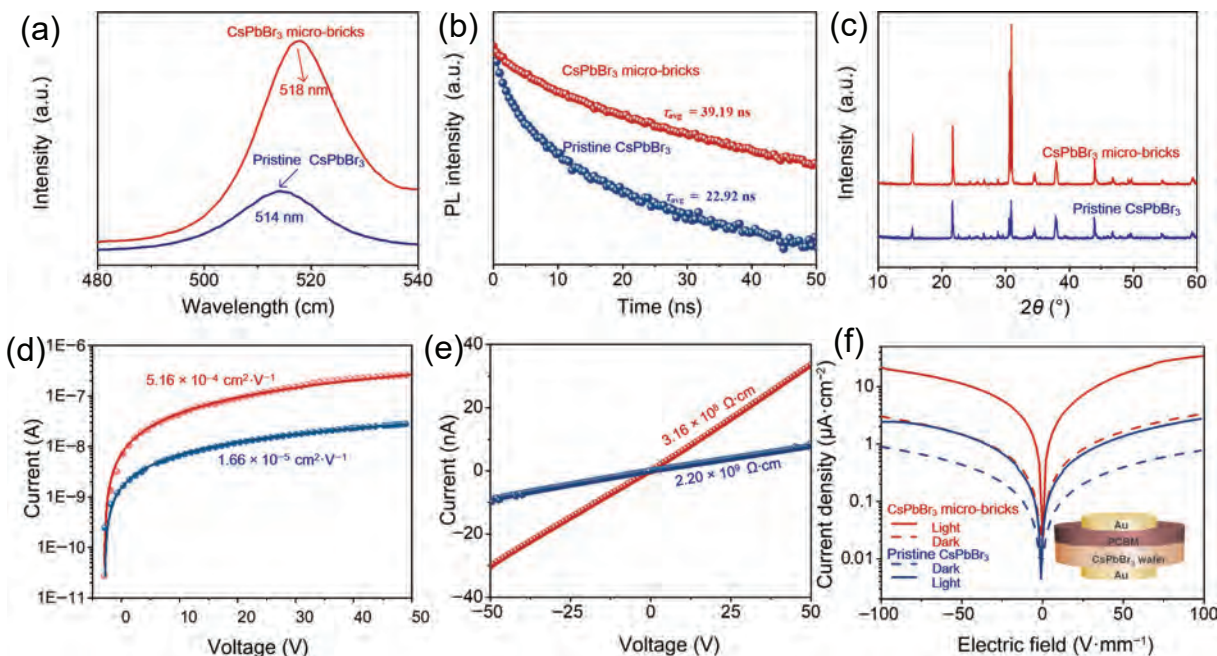


Figure 3 Optoelectronic properties of CsPbBr₃ wafer. (a) PL spectra, (b) TRPL spectra, (c) XRD patterns, (d) photoconductivity, and (e) resistivity of the pristine CsPbBr₃ and CsPbBr₃ micro-bricks wafer. (f) *J*-*V* characteristics of the pristine CsPbBr₃ and CsPbBr₃ micro-bricks detectors.

upon on/off X-ray switching. In general, the CsPbBr₃ micro-bricks detector shows a lower dark current density and larger X-ray on-off ratio than conventional detectors. To quantify the sensitivity of the two detectors, the X-ray generated current densities are plotted as a function of dose rates in Figs. 4(b) and 4(c). A linear relationship is observed between 1620 and 160 μGy_{air}·s⁻¹. The sensitivity can be calculated from the slope of the photocurrents versus X-ray dose rates plots acquired at different electric fields. The pristine CsPbBr₃ detector exhibits X-ray sensitivities of 798, 675, 521, and 252 μC·Gy_{air}⁻¹·cm⁻² at 100, 80, 60, and 40 V·mm⁻¹, respectively. In comparison, the CsPbBr₃ micro-bricks detector shows much higher sensitivity of 14,430, 9810, 5170, and 2640

μC·Gy_{air}⁻¹·cm⁻² at electric fields of 100, 80, 60, and 40 V·mm⁻¹, respectively.

To further assess the performance, the signal-to-noise ratio (SNR) based on the noise calculated from the standard deviation of the photocurrents is derived by the following Eq. (2)

$$SNR = I_{\text{signal}}/I_{\text{noise}} = (I_{\text{photo}} - I_{\text{dark}})/I_{\text{noise}} \quad (2)$$

where *I*_{signal} is the signal current, *I*_{noise} is the noise current, *I*_{photo} is the average current under X-ray irradiation, and *I*_{dark} is the average dark current derived from parallel experiments conducted at each bias. The SNRs of the detectors as a function of dose rates are plotted in Fig. 4(d). A large electric field of 100 V·mm⁻¹ is applied

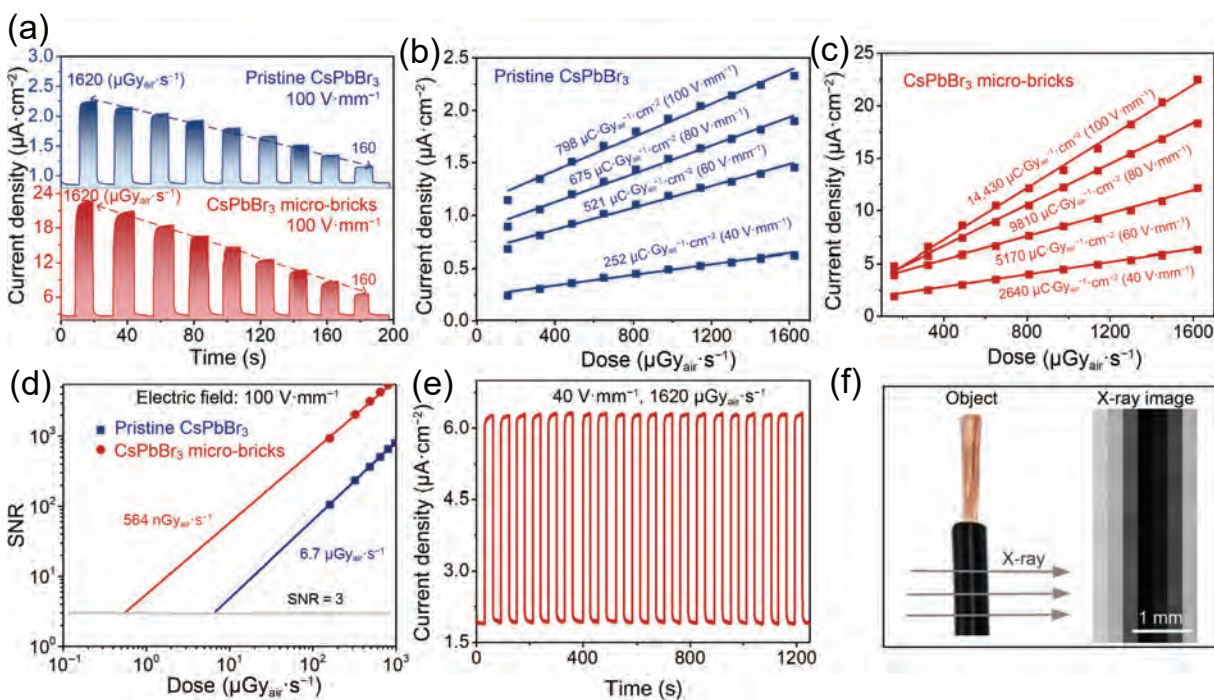


Figure 4 X-ray detection performance based on CsPbBr₃ wafer devices. (a) X-ray response profiles of the pristine CsPbBr₃ and CsPbBr₃ micro-bricks X-ray detectors. X-ray generated current densities as a function of dose rates at different applied electrical fields: (b) Pristine CsPbBr₃ and (c) CsPbBr₃ micro-bricks X-ray detector. (d) Dose rate dependent SNR of the detectors. (e) Stability of the pristine CsPbBr₃ detector under pulsed X-ray irradiation of 1620 μGy_{air}·s⁻¹. (f) Optical image and X-ray image of an electrical wire.

to the opposite electrodes to extract X-ray generated charges in the interior of the thick CsPbBr₃ wafer. The SNR exhibits a linear dependence with X-ray dose rates. According to the International Union of Pure and Applied Chemistry standard, the detector signal should maintain an SNR of over 3. As expected, the CsPbBr₃ micro-bricks detector shows a low limit-of-detection (LoD) of 564 nGy_{air}·s⁻¹ in contrast to 6.75 μGy_{air}·s⁻¹ for the conventional detector.

To evaluate the stability under normal operating conditions, X-ray on/off experiments are carried out for 30 s at a 40 V·mm⁻¹ external electric field and 1620 μGy_{air}·s⁻¹ X-ray dose and the results are presented in Fig. 4(e) and Fig. S18 in the ESM. Compared to the CsPbBr₃ detector, the CsPbBr₃ micro-bricks detector exhibits a more reproducible and stable response with small changes. Moreover, the device is placed in the ambient condition for a period of time to test the storage stability. After 14 days in air (25 °C, relative humidity 60%), the pristine CsPbBr₃ detector exhibits enhanced dark current but reduced photocurrent response, in contrast, the CsPbBr₃ micro-bricks detector maintains satisfactory device performance (Fig. S19 in the ESM). The X-ray imaging capability is assessed by x-γ scanning experiments, in which an electric wire is the imaging target. As shown in Fig. 4(f), the capability is confirmed.

4 Conclusions

A DMSO-based solution process is demonstrated to produce high-quality CsPbBr₃ micro-bricks for dense and compact microcrystalline perovskite wafers for X-ray detection. A large amount of CsPbBr₃ powder can be prepared by mechanical grinding. The CsPbBr₃ micro-bricks powder with a cubic shape, high crystallinity, and excellent optical properties is prepared. A trace amount of DMSO attaches to the CsPbBr₃ micro-bricks via Pb–O bonding to form the CsPbBr₃-DMSO adduct. During hot isostatic processing, the DMSO vapor released from CsPbBr₃-DMSO promotes CsPbBr₃ grain growth and merges CsPbBr₃ micro-bricks, resulting in a compact and dense wafer with a large grain size and minimized grain boundaries. The CsPbBr₃ micro-bricks wafer has excellent optoelectronic properties as exemplified by a large μτ product of 5.16 × 10⁻⁴ cm²·V⁻¹, and the X-ray detector exhibits high sensitivity of 14,430 μC·Gy_{air}⁻¹·cm⁻², low detection limit of 564 nGy_{air}·s⁻¹, as well as robust stability. The results reveal an efficient strategy to design and produce sensitive and sturdy X-ray detectors.

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Electronic Supplementary Material: Supplementary material (further details of the characterization, SEM images, AFM images,

KPFM images, schematic illustration, XRD patterns, XPS spectra, FTIR spectra, UPS spectra, and stability tests) is available in the online version of this article at <https://doi.org/10.1007/s12274-023-5487-3>.

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Electronic Supplementary Material

CsPbBr₃-DMSO merged perovskite micro-bricks for efficient X-ray detection

Tongyu Shi^{1,2,§}, Wenjun Liu^{1,3,§}, Jiongtao Zhu¹, Xiongsheng Fan¹, Zhengyu Zhang¹, Xingchen He¹, Rui He¹, Jiahong Wang^{1,2}, Kezhen Chen^{1,2}, Yongshuai Ge^{1,2}, Xiangming Sun⁴, Yanliang Liu^{1,2} (✉), Paul K. Chu⁵, and Xue-Feng Yu^{1,2} (✉)

¹ Shenzhen Institute of Advanced Technology, Chinese Academy of Sciences, Shenzhen 518055, China

² University of Chinese Academy of Sciences, Beijing 100049, China

³ Nano Science and Technology Institute, University of Science and Technology of China, Suzhou 215123, China

⁴ Key Laboratory of Quark and Lepton Physics (MOE), Central China Normal University, Wuhan 430079, China

⁵ Department of Physics, Department of Materials Science and Engineering, and Department of Biomedical Engineering, City University of Hong Kong, Hong Kong 999077, China

[§] Tongyu Shi and Wenjun Liu contributed equally to this work.

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Address correspondence to Yanliang Liu, yl.liu4@siat.ac.cn; Xue-Feng Yu, xf.yu@siat.ac.cn

Characterization

The morphology of the CsPbBr₃ powder and wafer was examined by scanning electron microscopy (SEM, Zeiss GeminiSEM 300) and atomic force microscopy (Bruker, USA). The chemical structure of the powder were determined by Fourier-transform infrared spectroscopy (FT-IR, Thermo Scientific, Nicolet iS50) according to the KBr pellet method. Powder X-ray diffraction (XRD) was performed on the Rigaku Smartlab 3kW X-ray diffractometer with Cu K_α radiation ($\lambda = 1.54056 \text{ \AA}$, 40 kV, 30 mA, 10° min⁻¹ from 10 to 60°) and the UV–vis absorption spectra were obtained on a UV–vis spectrometer (UV-1800, Shimadzu). Raman scattering was conducted on the Horiba Jobin Yvon LabRam HR-VIS high-resolution confocal Raman microscope equipped with a 633 nm laser. The PL and TRPL properties were determined using a fluorescent spectrophotometer (Hitachi F-4600 and Edinburgh FLS-1000) at an excitation wavelength at 365 nm. The XPS measurements were carried out on an ESCALAB 250Xi spectrometer (Thermo Scientific, USA) equipped with a pass energy of 30 eV with a power of 100 W (10 kV and 10 mA) and a mono-chromatized AlK_α X-ray ($h\nu=1486.65 \text{ eV}$) source. Ultraviolet photoemission spectroscopy (UPS) was performed on an ESCALAB 250Xi electron spectrometer (Thermo Fisher Scientific) using a monochromatic Al K_α source (300 W). UPS was carried out under a pressure of about $2 \times 10^{-10} \text{ Pa}$ using helium I_α (21.22 eV) radiation from a discharge lamp operated at 90 W, a pass energy of 1 eV, and a channel width of 25 meV, and the energy resolution was 0.02 eV. A -10 V bias was applied to the samples, in order to separate the sample and analyze low-kinetic-energy cutoffs.

Device characterization

The X-ray detection characteristics were evaluated using an X-ray generation system for medical imaging (Varex, G242, 18932-M8, USA). The accelerating voltage was 50 kV and the currents were varied from 10 to 200 uA. The dose rate of the X-rays was calibrated by the X2 CT dosimeter (Unfors Raysafe, Sweden). During the measurement conducted in darkness, the external electrical bias and current were

recorded by the PDA FS380 semiconductor analyzer. The X-ray imaging capability of the detector was demonstrated by moving the object between the detector (1 mm^2) and X-ray beam ($1620 \mu\text{Gy}_{\text{air}} \text{ s}^{-1}$) using a self-assembled x-y scanning system consisting of a motorized linear displacement stage (Newport, M-IMS400CC). A motorized linear displacement stage and motion controller (Newport, M-IMS400CC) were used to control scanning along the x and y axes.



Figure S1. CsPbBr₃ powder synthesized by mechanical grinding.

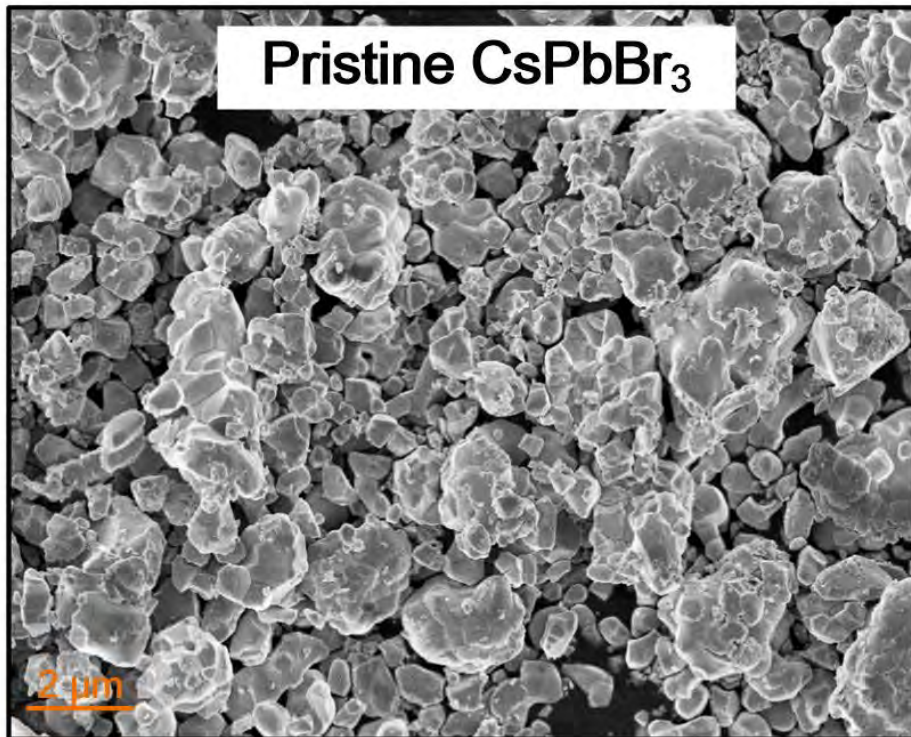


Figure S2. SEM image of the pristine CsPbBr₃ powder.

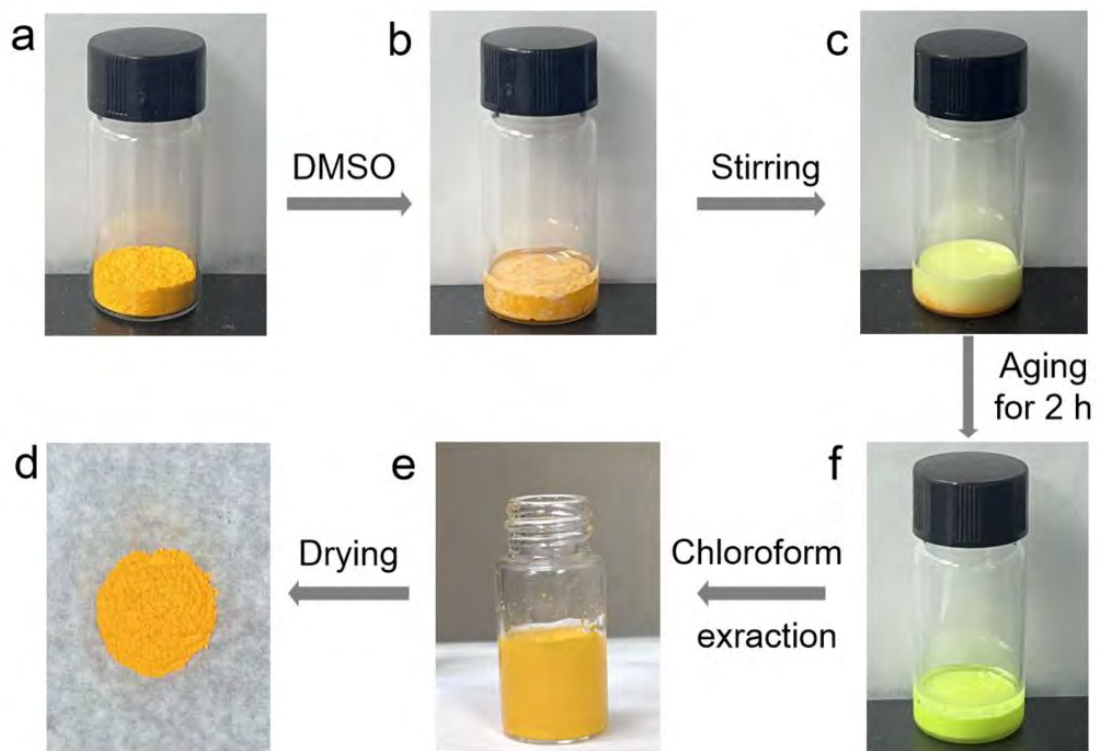


Figure S3. Schematic illustration of preparation of CsPbBr₃ in DMSO.

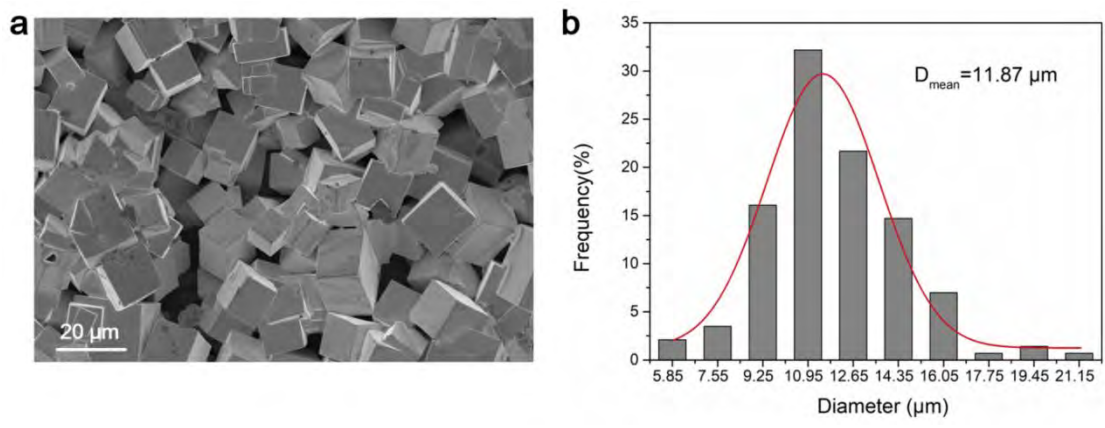


Figure S4. (a) SEM image of CsPbBr₃ microbricks and (b) particle size distribution histogram).

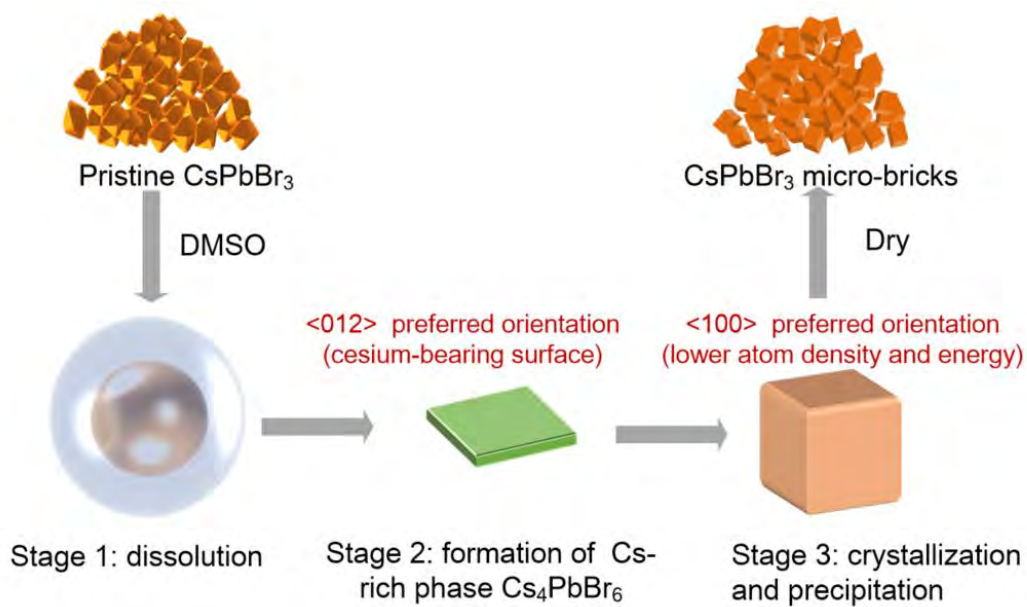


Figure S5. Mechanism proposed for the formation of CsPbBr_3 micro-bricks.

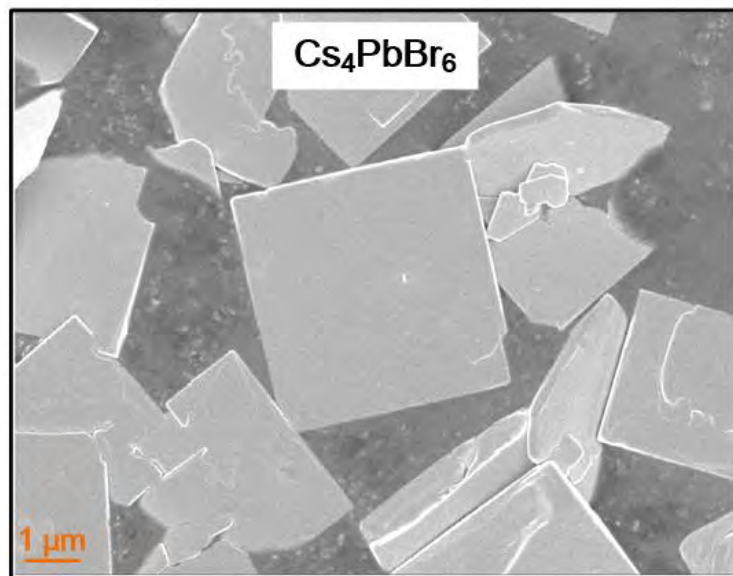


Figure S6. SEM image of the cultivated Cs₄PbBr₆.

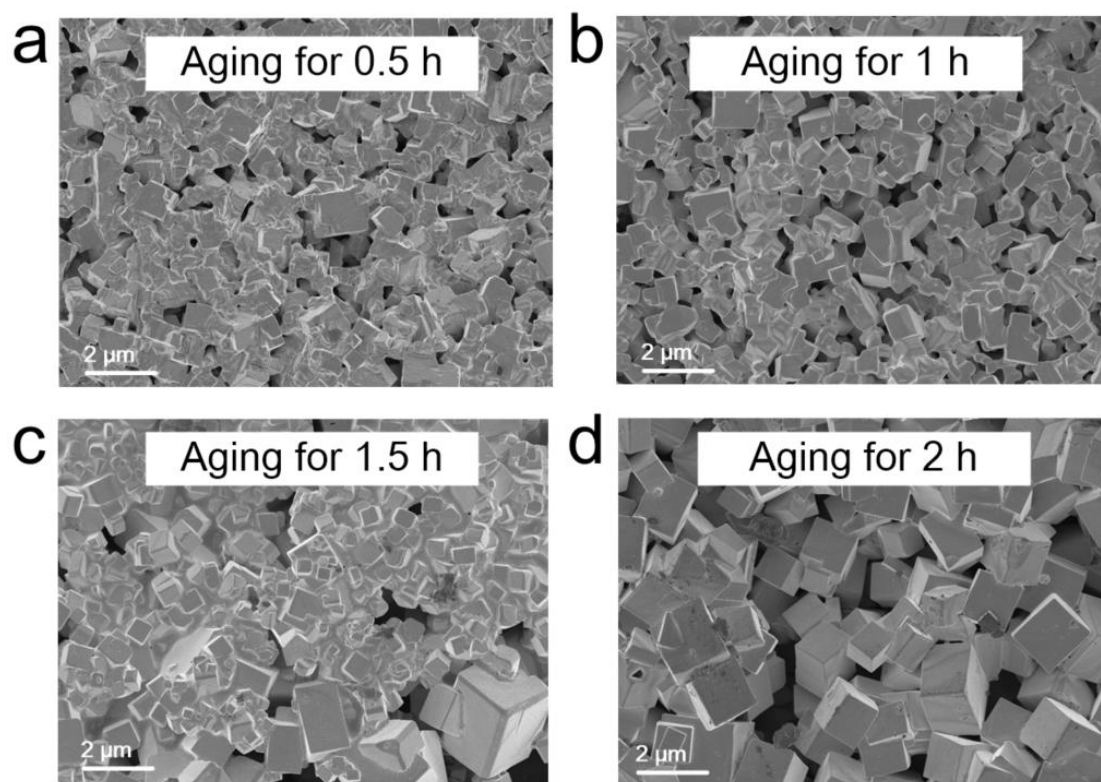


Figure S7. SEM images of the CsPbBr₃ obtained at different aging time (from 0.5 h to 2 h).

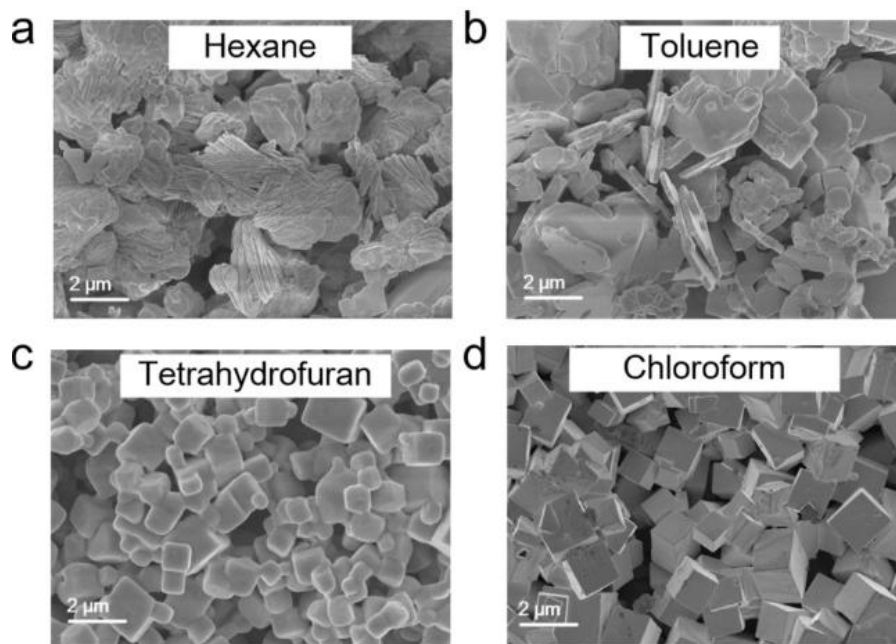


Figure S8. SEM images of the CsPbBr₃ obtained from the reactions carried out in different solvent (hexane, toluene, tetrahydrofuran, and chloroform).

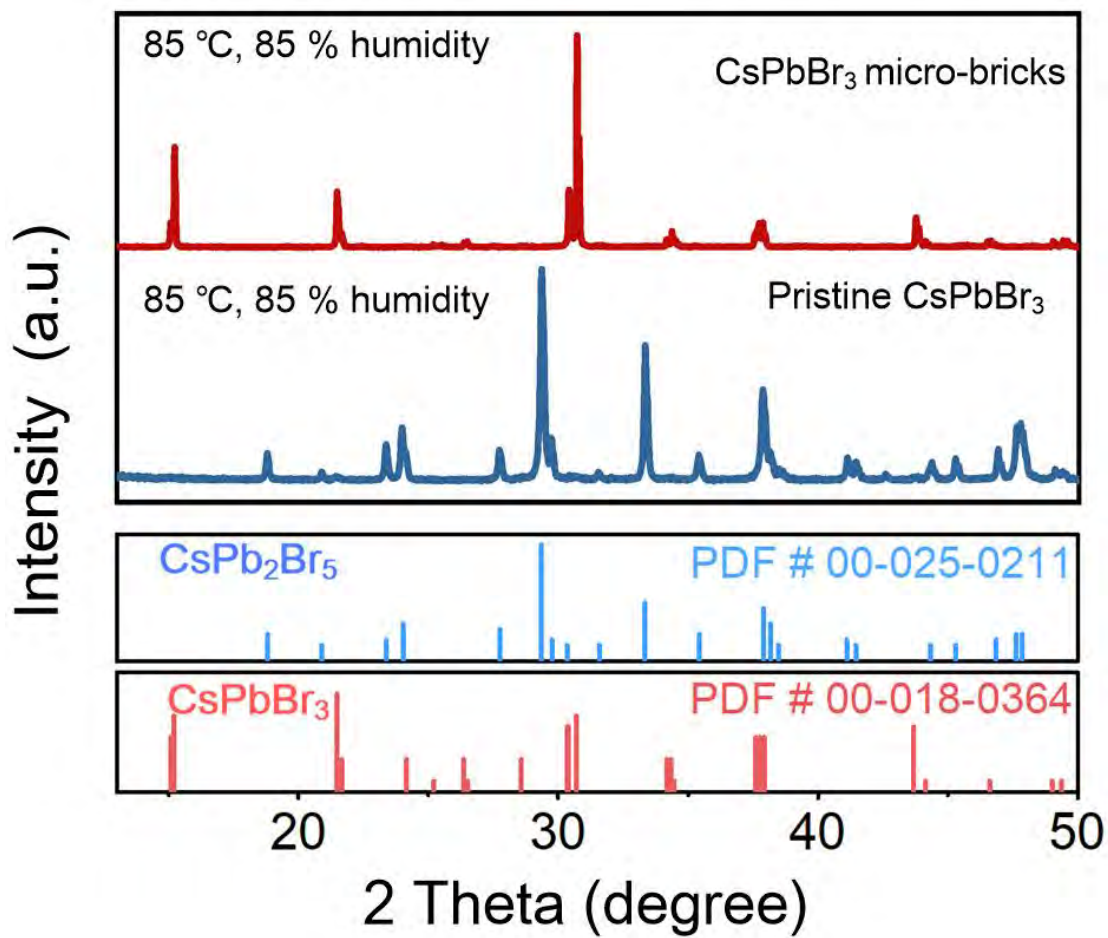


Figure S9. XRD patterns of pristine CsPbBr₃ and CsPbBr₃ micro-bricks after 21 days of aging under 85 °C and 85% relative humidity.

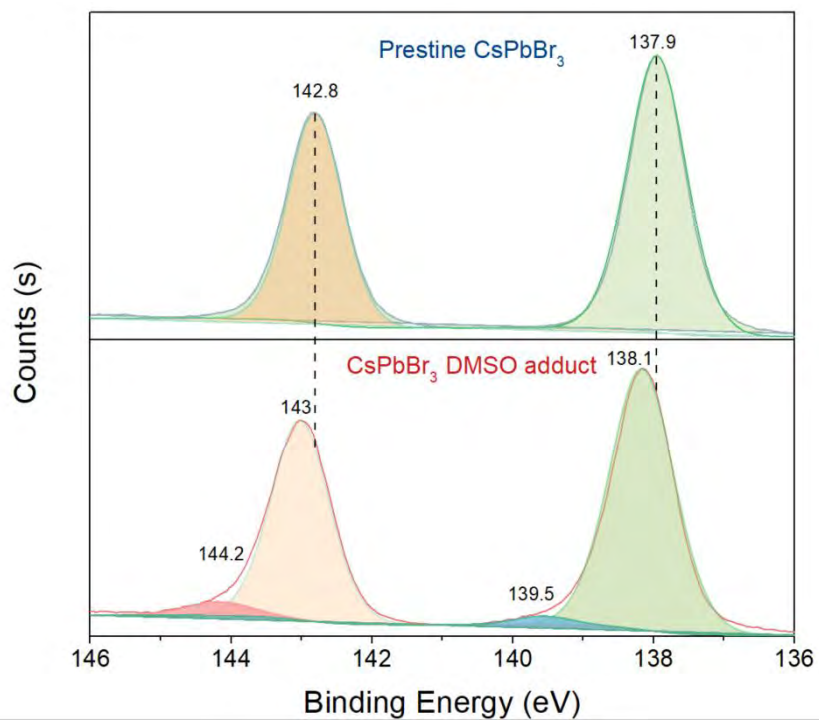


Figure S10. High-resolution Pb 4f spectra of pristine CsPbBr₃ and CsPbBr₃-DMSO adduct.

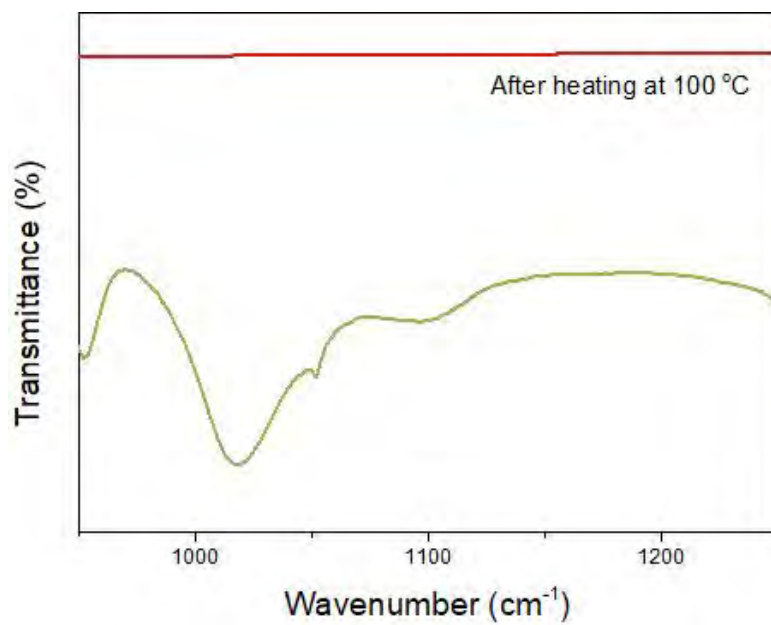


Figure S11. FTIR spectra of the CsPbBr₃ micro-bricks after heating at 100 °C.

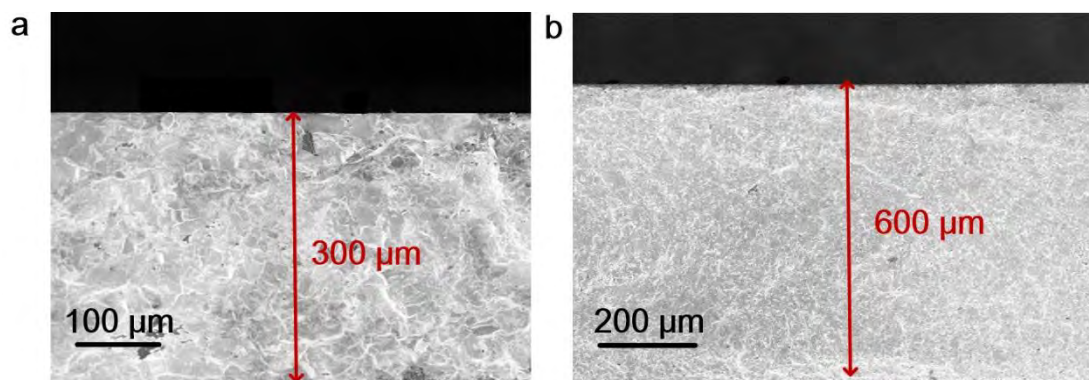


Figure S12. Cross-section SEM images of CsPbBr₃ micro-bricks wafer.

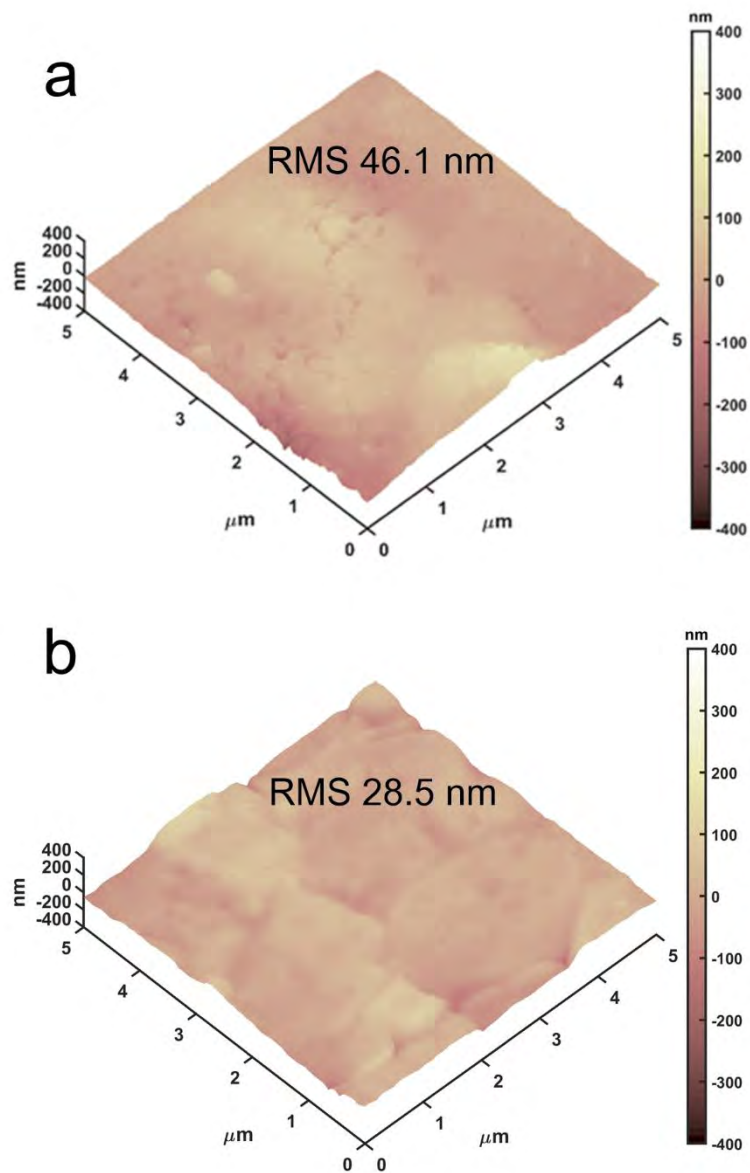


Figure S13. AFM images: (a) pristine CsPbBr₃ and (b) CsPbBr₃ micro-bricks wafers.

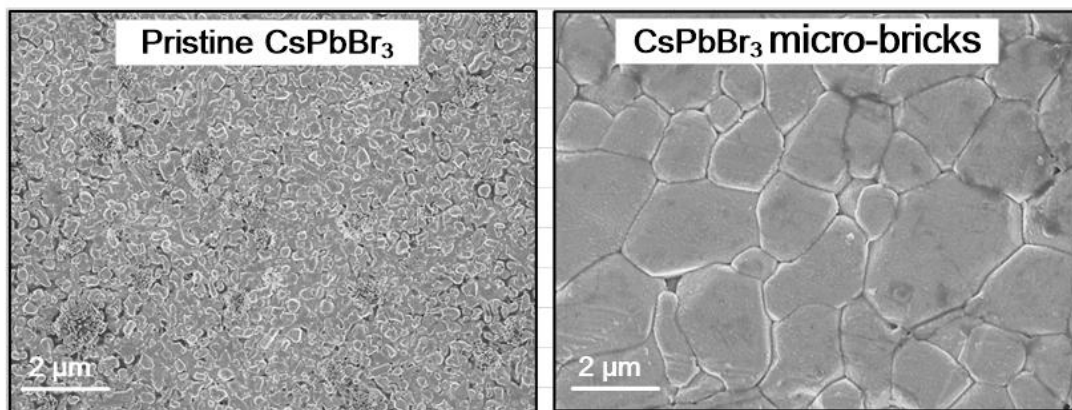


Figure S14. SEM images of pristine CsPbBr₃ and CsPbBr₃ micro-bricks wafers after 14 days under 25 °C and 60% relative humidity.

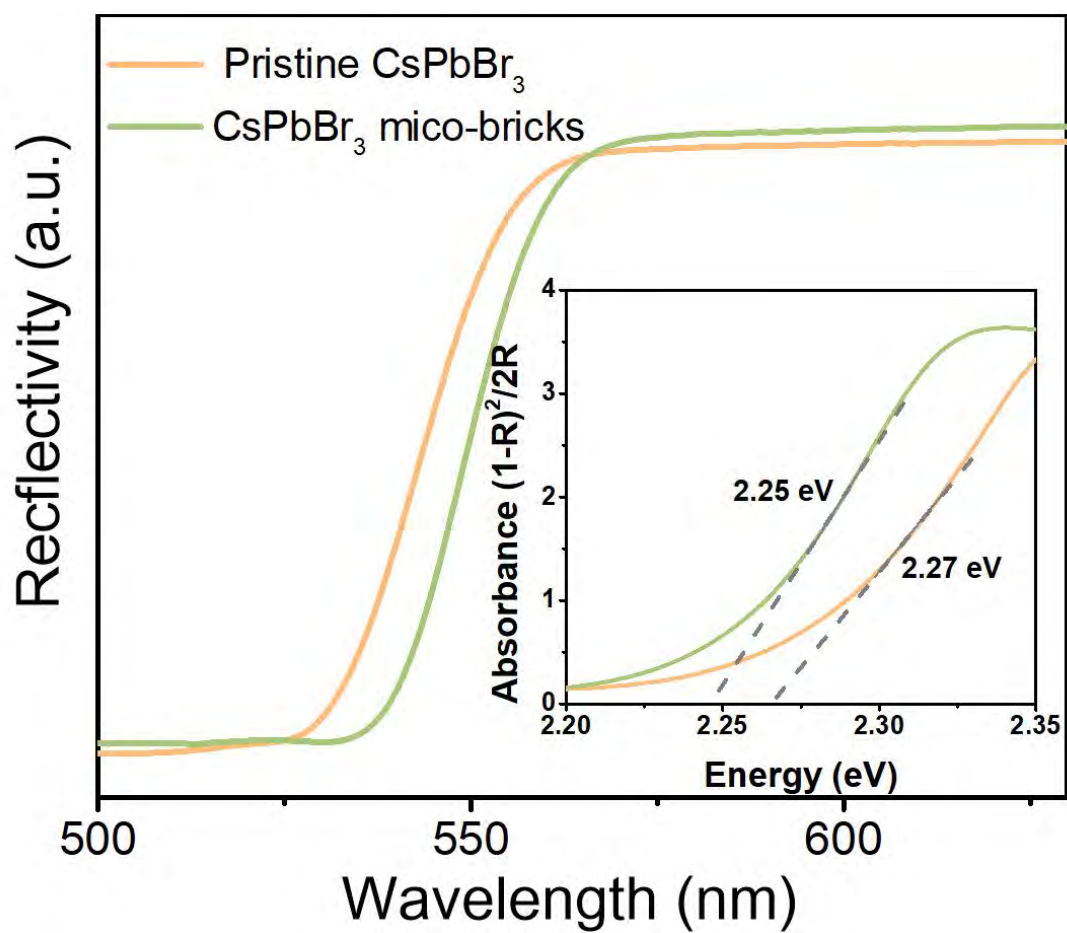


Figure S15. UV-vis spectra of the pristine CsPbBr₃ and CsPbBr₃ micro-bricks (inset showing the Tauc plot).

Table S1. Fitting parameters and average lifetime of the wafers

	A_1	τ_1 [ns]	A_2	τ_2 [ns]	T_{avg}
Pristine CsPbBr₃	4276.50778	11.74227	24009.86006	2.29315	6.800394059
CsPbBr₃ micro-bricks	4042.45622	33.07301	8278.46088	5.70064	25.93176172

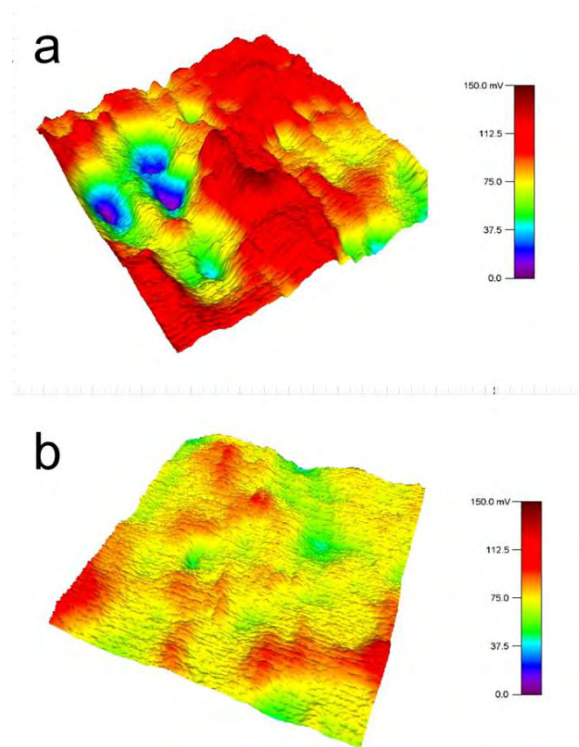


Figure S16. KPFM images of (a) pristine CsPbBr₃ and (b) CsPbBr₃ micro-bricks wafers.

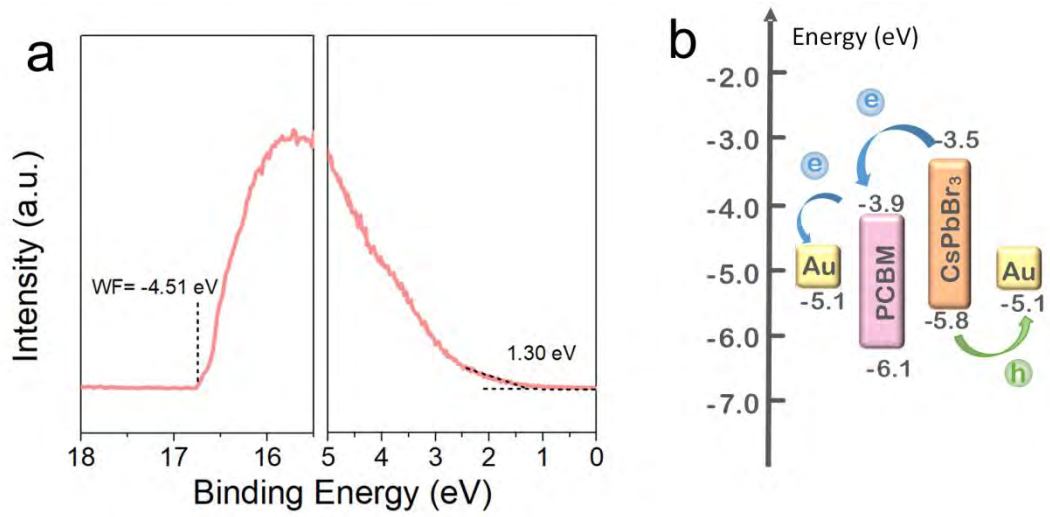


Figure S17. UPS spectra and energy level diagram of perovskite X-ray detector.

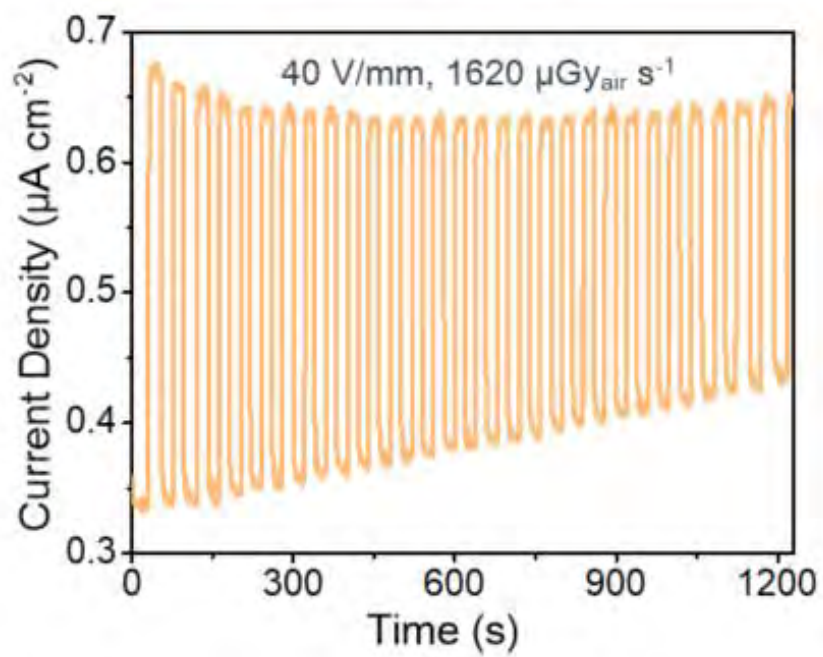


Figure S18. Stability of the pristine CsPbBr₃ detector under pulsed X-ray irradiation at a fixed dose rate.

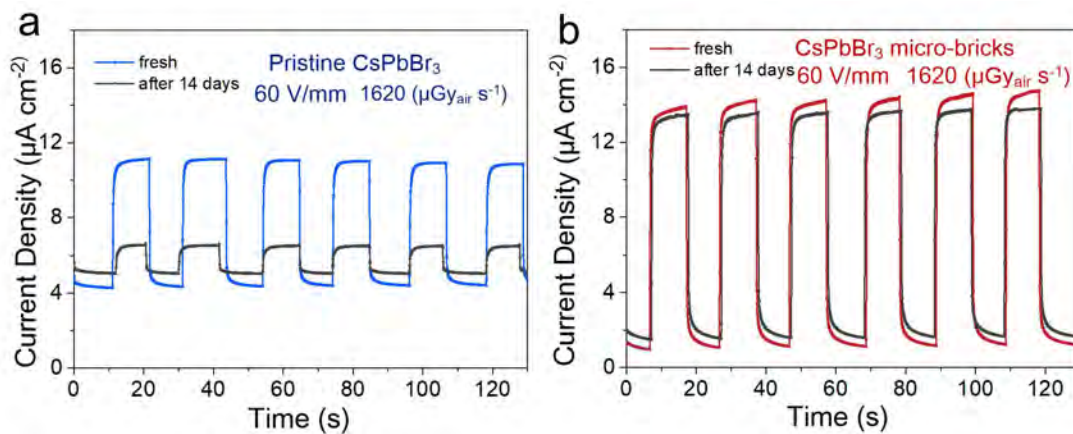


Figure S19. The storage stability of (a) pristine CsPbBr₃ and (b) CsPbBr₃ micro-bricks detector in ambient condition (25 °C, relative humidity 60%).